

Appln. No.: 10/774,023
Amendment Dated May 15, 2006
Reply to Office Action of February 15, 2006

MKPA-108US

Amendments to the Specification:

Please replace paragraph [0036] with the following rewritten paragraph:

[0036] In one embodiment of the present invention, a highest threshold range may be, for example, characterized by a coupled optical power measure that is greater than or equal to 95% of a maximum power value; a first intermediate threshold range may be, for example, characterized by a coupled optical power measure that is greater than or equal to 60% of the maximum power value; and a lowest threshold range may be, for example, characterized by a coupled optical power measure that is greater than about 5% of the maximum power value. The maximum power value may be a predetermined value, or the maximum value of optically coupled power that is measured in any iteration of the scan according to the method shown in Fig. 5. In a further embodiment, a highest-lowest resolution setting may be characterized by 700-800 nm step size (i.e., the distance between the center data point and any vertex data point); a first intermediate resolution setting may be characterized by 350-450 nm step size; and a lowest-highest resolution setting may be characterized by 80-150 nm step size. Alternately, a highest-lowest resolution setting may be characterized by 5-7 micron horizontal step size and 700-800 nm vertical step size; a first intermediate resolution setting may be characterized by 1.5-2.5 micron horizontal step size and 350-450 nm vertical step size; and a lowest-highest resolution setting may be characterized by 250-350nm horizontal step size and 80-150 nm vertical step size.